

<b>Notice of References Cited</b>	Application/Control No. 10/589,227		Applicant(s)/Patent Under Reexamination KEMP ET AL.	
	Examiner Janet L. Epps-Smith		Art Unit 1633	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0031067	02-2004	Herlyn et al.	800/9
*	B	US-7,196,054	03-2007	Drohan et al.	514/2
*	C	US-2002/0018757	02-2002	Harichian et al.	424/59
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
X	N	WO 02072113 A1	09-2002	World Intellect	LEEK et al.	
	O					
	P					
	Q					
	R					
	S					
	I					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.